



The Testcenter facility 'LoRa<sup>®</sup> Test Lab' within IMST GmbH is recognized by the LoRa<sup>®</sup> Alliance for testing in accordance to the LoRaWAN<sup>®</sup> Specification V1.0.2

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# Report for Certification by Similarity according to LoRaWAN<sup>®</sup> V1.0.2

for the Device

**“5XX1N-XX-X-X1“**

for the Customer

**“TE Connectivity Sensors”**

Jens Lerner  
Yavuz Turan

7<sup>th</sup> August, 2023

## Administrative Summary

Location: IMST GmbH, Test Centre, Kamp-Lintfort, Germany

Responsible Test Engineer: Yavuz Turan, Jens Lerner

Subject: Test of Conformance to LoRaWAN® Specification V1.0.2

Company and Contact Information:

TE Connectivity Sensors

Marty Romain

4 rue Gaye Marie

31000 Toulouse

French

Checked Device: 5XX1N-XX-X-X1

Hardware version: B

Firmware version: 3.3

Type and Version of used Stack: Stackforce, 4.6.0 Master Version

Original End-device identifier: 8911N

LoRa Device Class: A

LoRaWAN Specification version: V1.0.2

Certification requirements: LoRa End Device Certification by Similarity V1.1

Frequency band(s): EU868&US915 MHz

Type of Certification by Similarity:

Case 2: Certification of an end-device variant from a certified end-device

Variant device differences to the referenced certified device:

- Same LoRa transceiver
- Same LoRaWAN protocol SW version
- Same MCU Core
- Same Clock design and implementation

Brief description of the differences between the primary and the variant device

Change of sensor type

Date: 7<sup>th</sup> August, 2023

The Test Report, No. 6230404 has the following conclusion:

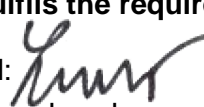
**The device fulfils the requirements.**

Responsibility:

  
Yavuz Turan

Test Engineer

Approved:

  
Jens Lerner

Quality Engineer

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